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Substitute for form 1449A/B/PTO		<b>Complete If Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)		Application Number	10/672,961 (Conf. No. 9439)
		Filing Date	September 26, 2003
		First Named Inventor	Glenn J. Leedy
		Art Unit	2822
		Examiner Name	Monica Lewis
Sheet	1	of	2
		Attorney Docket Number	ELM-2 Cont. 4

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.	Document Number Number-Kind Code* (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Initials*	Cite No.	Foreign Patent Document Country Code*-Number-Kind Code* (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Signature	<i>Call</i>	Date Considered	11/10/07
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Sheet	2	of	2	Attorney Docket Number	ELM-2 Cont. 4

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume- issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
		Wolf, Stanley and Richard N. Tauber; Silicon Processing For the VLSI Era, Volume 1: Process Technology; Sunset Beach, CA: Lattice Press, 1986, pages 191-194	
		European Search Report for Application No. EP-02-00-9643 (date completed: October 8, 2002)	
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/TD/ 3/7/10

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